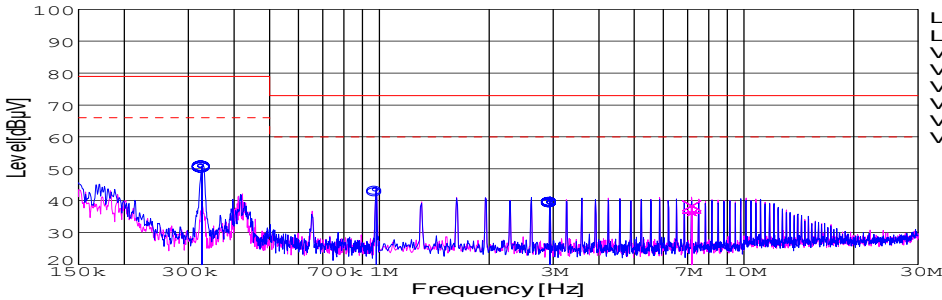
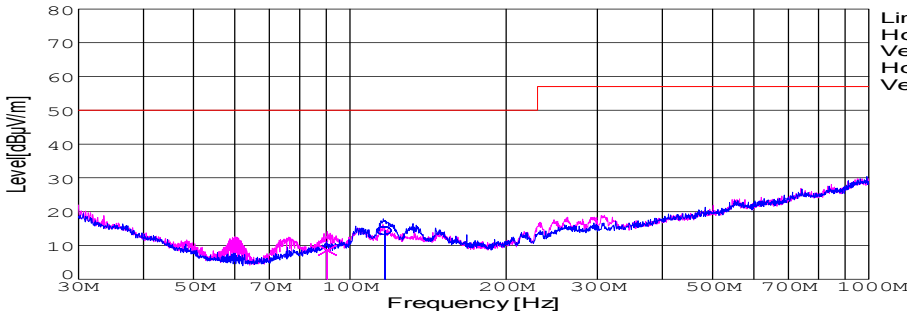


DATA SHEET							Date	10-Mar-05		
Model	SUW64815						Temp.	25 degreeC		
Test	EMI Line conduction & Radiated emission						Humid.	45 %RH		
							Tested by	Y.Hirose		
LINE CONDUCTION										
Model Name : SUW64815				Temp. : 25						
Model No. :				Humi. : 45						
Serial No. :				Date : 2005/3/10 11:53						
Points : 4				Test Equip. : R3132,ESPC						
Detector : PEAK/QP/Ave.				Comment : Y.Hirose						
Line Mode : VA/VB				+15V0.2A						
Power Supply : DC 48V				-15V0.2A						
Limit1: [EN 55022] Class A(QP)										
Limit2: [EN 55022] Class A(Ave.)										
							Limit1(QP) ——— Limit2(Ave.) - - - VA(PEAK) ——— VB(PEAK) ——— VA(QP) ○ VA(Ave.) ● VB(QP) × VB(Ave.) *			
							DC 48V +15V0.2A -15V0.2A			
Frequency [MHz]	Meter Reading (Ave.) [dBuV]	Meter Reading (QP) [dBuV]	Factor [dB]	Level(Ave.) [dBuV]	Level(QP) [dBuV]	Line	Limit(Ave.) [dBuV]	Limit(QP) [dBuV]	Margin(Ave.) [dB]	Margin(QP) [dB]
0.3263	41	40.4	9.8	50.8	50.2	VA	66	79	15.2	28.8
0.9797	33.2	32.7	9.9	43.1	42.6	VA	60	73	16.9	30.4
2.9406	29.5	29.1	9.9	39.4	39	VA	60	73	20.6	34
7.1918	26	28.3	10.1	36.1	38.4	VB	60	73	23.9	34.6
RADIATED EMISSION										
Model Name : SUW64815				Temp. : 25						
Model No. :				Humi. : 45						
Serial No. :				Date : 2005/3/10 13:14						
Points : 2				Test Equip. : R3132,ESPC						
Detector : PEAK/QP				Comment : Y.Hirose						
Polarization : Hori. & Vert.				+15V0.2A						
Power Supply : DC 48V				-15V0.2A						
Limit: [EN 55022] Class A<3m>										
							Limit(QP) ——— Horizontal(PEAK) ——— Vertical(PEAK) ——— Horizontal(QP) ○ Vertical(QP) ×			
							DC 48V +15V0.2A -15V0.2A			
Frequency [MHz]	MeterReading (QP) [dBuV]	Ant. Type	Antenna Factor [dB/m]	Cable & Preamp [dB]	Level(QP) [dBuV/m]	Angle [°]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]
116.996	35.1	BL	10.9	-31.7	14.3	340	142	Hori.	50	35.7
90.492	31.8	BL	8.6	-31.8	8.6	238	133	Vert.	50	41.4

COSEL

Conditions

Test : EMI
Model Name : SUS/SUW 648□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

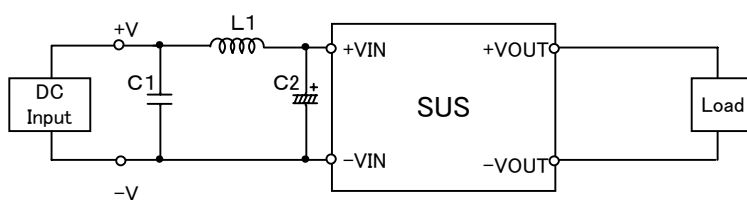


Fig.1 Testing circuitry 1

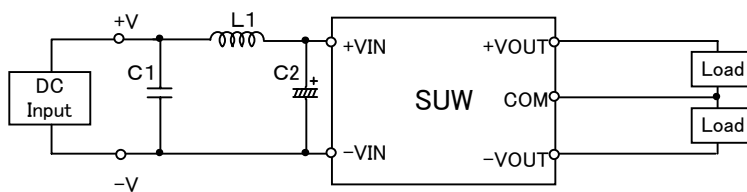


Fig.2 Testing circuitry 2

L1 :	6.8 μ H	CY3H-6R8	(KORIN ELECTRONICS)
C1 :	100V 1 μ F	C3225JB2A105M	(TDK)
C2 :	100V 47 μ F	UPW2A470M	(NICHICON)